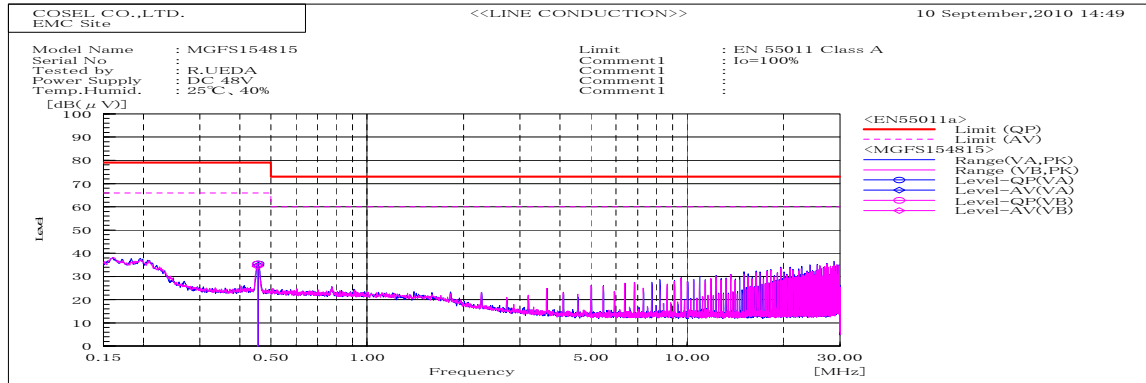
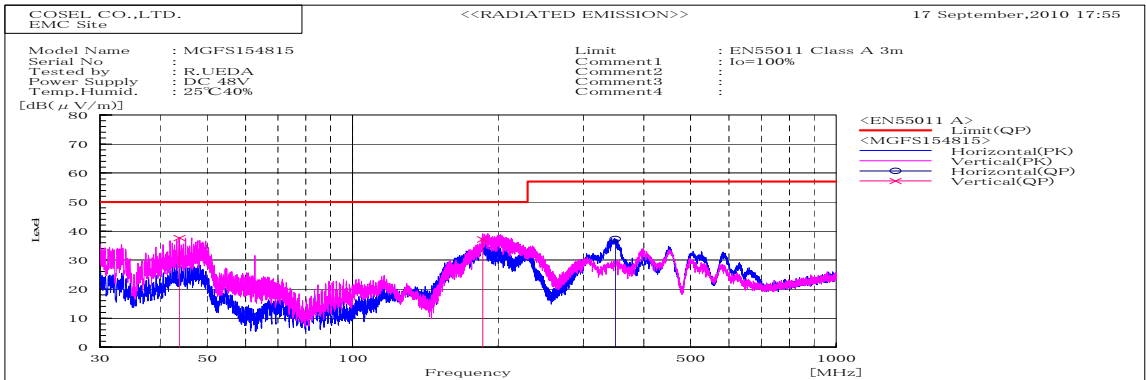


DATA SHEET		Date	21-Sep-10
Model	MGFS154815	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.45453		VB	25.3	24.4	10	35.3	34.4	79	66	43.7	31.6	Pass	
0.45714		VA	25.3	24.7	10.1	35.4	34.8	79	66	43.6	31.2	Pass	

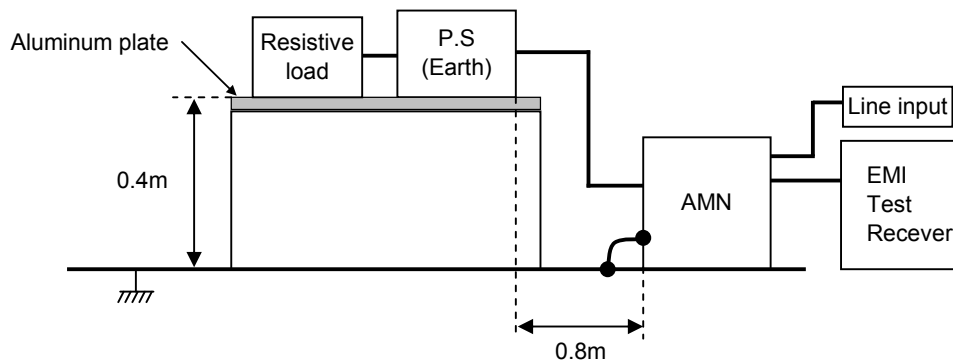


Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
43.804	V	Stable	58.2	-20.6		37.6		50	12.4	Pass	103	312	
185.889	V	Stable	59.3	-22.2		37.1		50	12.9	Pass	113	97	
349.2	H	Stable	53.6	-16.3		37.3		57	19.7	Pass	109	160	

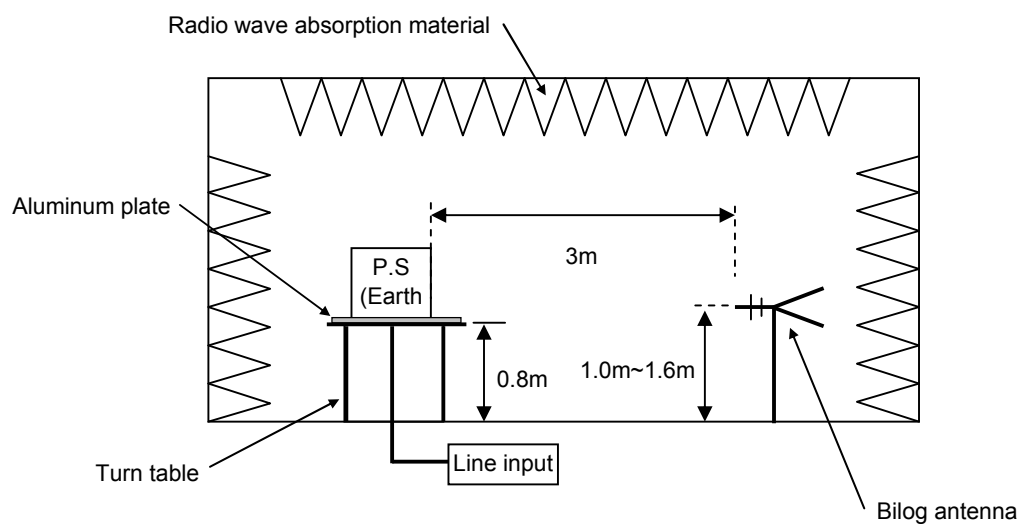
## DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

### 1. Line conduction



### 2. Radiated emission

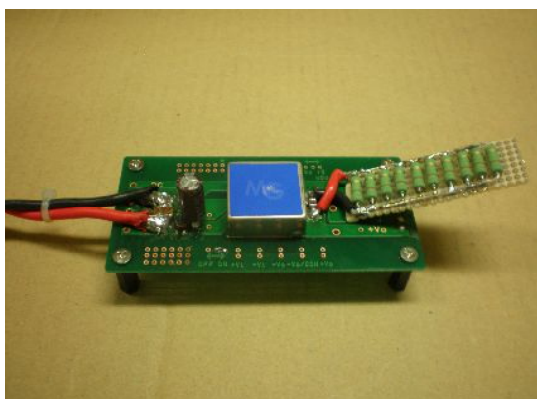


## Conditions

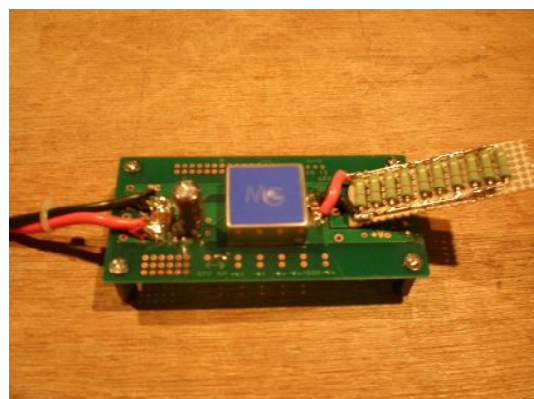
Test : EMI  
Model Name : MGFS1548□□/MGFW1548□□

○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry

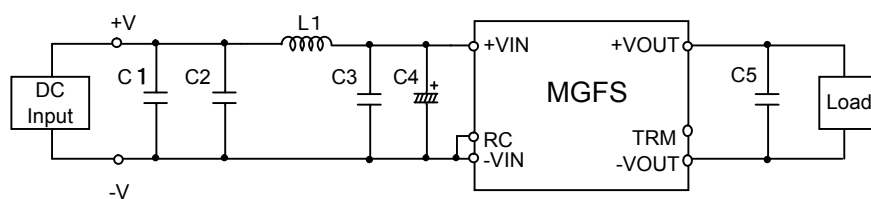


Fig.1 Testing circuitry 1

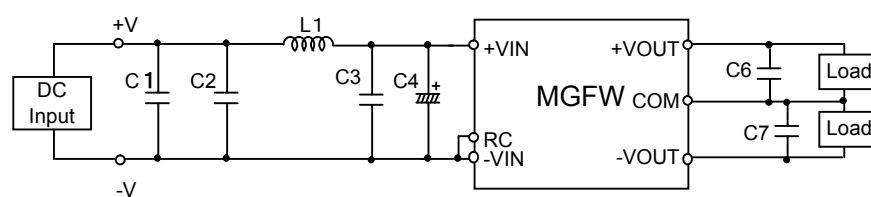


Fig.2 Testing circuitry 2

L1	: 10 $\mu$ H	CI4C-100	(KORIN ELECTRONICS)
C1,C2,C3	: 100V	2.2 $\mu$ F	C4532JB2A225MT (TDK)
C4	: 80V	47 $\mu$ F	LXV80VB47M (NIPPON CHEMI-CON)
C5,C6,C7	: 25V	22 $\mu$ F	CM32X5R226K25A (KYOCERA)